



TET ESTEL AS
ESTONIA

June
2013

Series
TFI172-200

Fast Stud Mounted Thyristor
Type TFI172-200

Low turn-off time
Low reverse recovery charge
Distributed amplified gate for high di/dt

Maximum mean on-state current						I_{TAV}	200 A			
Maximum repetitive peak off-state and reverse voltage						U_{DRM}	300 ÷ 1100 V			
Turn-off time						U_{RRM}				
						tq	12,5; 16; 20 μs			
U_{DRM}, U_{RRM}, V	300	400	500	600	700	800	900	1000	1100	
Voltage code	3	4	5	6	7	8	9	10	11	
$T_{vj}, °C$	- 60 ÷ 125									

MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	TFI172-200	Conditions
I_{TAV}	Mean on-state current	A	200	$T_c=95 °C$, 180° half-sine wave, 50 Hz
I_{TRMS}	RMS on-state current	A	314	$T_c=95 °C$
I_{TSM}	Surge on-state current	kA	6,0 6,6	$T_{vj}=125 °C$ $T_{vj}=25 °C$ tp=10 ms $U_R=0$
I^2t	Limiting load integral	kA ² s	180 217	$T_{vj}=125 °C$ $T_{vj}=25 °C$
U_{DRM}, U_{RRM}	Repetitive peak off-state and reverse voltage	V	300÷1100	$T_j \min \leq T_{vj} \leq T_{jM}$ 180° half-sine wave, 50 Hz Gate open
U_{DSM}, U_{RSM}	Non-repetitive peak off-state and reverse voltage	V	330÷1210	$T_j \min \leq T_{vj} \leq T_{jM}$ 180° half-sine wave tp=10 ms, Single pulse Gate open
(diT/dt) crit	Critical rate of rise of on-state current : non - repetitive repetitive	A/μs	1600 800	$T_{vj}=125 °C$; $U_D=0,67 U_{DRM}$, Gate pulse : 10V, 5 μs, 1 μs rise time, 10 μs
U_{RGM}	Peak reverse gate voltage	V	5	$T_j \min \leq T_{vj} \leq T_{jM}$
T_{stg}	Storage temperature	°C	-60÷80	
T_{vj}	Junction temperature	°C	-60÷125	

CHARACTERISTICS

U_{TM}	Peak on-state voltage	V	2,1	$T_{vj}=25 °C$, $I_{TM}=3,14 I_{TAV}$
$U_{T(TO)}$	Threshold voltage	V	1,4	$T_{vj}=125 °C$
R_T	On-state slope resistance	mΩ	0,75	1,57 $I_{TAV} < I_T < 4,71 I_{TAV}$
I_{DRM} I_{RRM}	Repetitive peak off-state and reverse current	mA	50 50	$T_{vj}=125 °C$, $U_D = U_{DRM}$ $U_R = U_{RRM}$

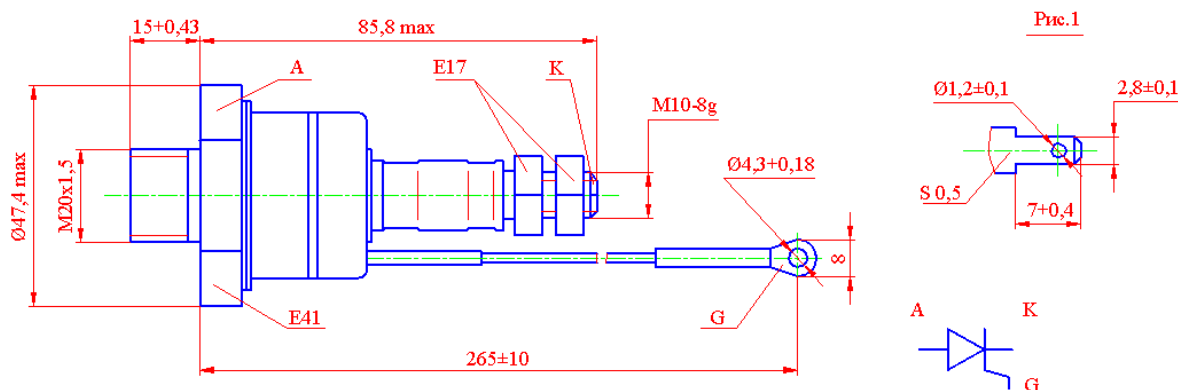
CHARACTERISTICS

Symbols and parameters		Units	TFII 72-200	Conditions
I_L	Latching current	A	5	$T_{vj}=25^{\circ}\text{C}, U_D=12\text{V}$ Gate pulse : 10V, 5 μs , 1 μs rise time, 10 μs
I_H	Holding current	A	0,3	$T_{vj}=25^{\circ}\text{C}, U_D=12\text{V}$, Gate open
U_{GT}	Gate trigger direct voltage	V	2,5 5,0	$T_{vj}=25^{\circ}\text{C}$, $T_{vj}=-60^{\circ}\text{C}$ $U_D=12\text{V}$
I_{GT}	Gate trigger direct current	A	0,3 0,85	$T_{vj}=25^{\circ}\text{C}$, $T_{vj}=-60^{\circ}\text{C}$
U_{GD}	Gate non-trigger direct voltage	V	0,25	$T_{vj}=125^{\circ}\text{C}$, $U_D = 0,67 U_{DRM}$
I_{GD}	Gate non-trigger direct current	mA	10	Direct gate current
t_{gd}	Delay time	μs	1,0 \div 1,6	$T_{vj}=25^{\circ}\text{C}, U_D=300\text{V}$ $I_{TM} = 200\text{ A}$
t_{gt}	Turn-on time	μs	1,6 \div 2,5	Gate pulse : 10V, 5 μs , 1 μs rise time, 10 μs
t_q	Turn-off time	μs	12,5 \div 20	$T_{vj}=125^{\circ}\text{C}$, $I_{TM}=200\text{ A}$ $di_R/dt = 10\text{ A}/\mu\text{s}$, $U_R=100\text{V}$ $U_D = 0,67 U_{DRM}$ $du_D/dt=50\text{ V}/\mu\text{s}$
Q_{rr}	Recovered charge	μC	100	$T_{vj}=125^{\circ}\text{C}$, $I_{TM}=200\text{ A}$ $di_R/dt = 50\text{ A}/\mu\text{s}$, $U_R=100\text{V}$
t_{rr}	Reverse recovery time	μs	3,1	
I_{RM}	Peak reverse recovery current	A	70	
$(du_D/dt)_{crit}$	Critical rate of rise of off-state voltage	V/ μs	500 1000	$T_{vj}=125^{\circ}\text{C}$, $U_D = 0,67 U_{DRM}$ Gate open
R_{thjc}	Thermal resistance junction to case	$^{\circ}\text{C}/\text{W}$	0,075	Direct current

ORDERING

	TFI	172	200	10	7	8	3	
	1	2	3	4	5	6	7	

- Fast thyristor with interdigitated gate structure.
- Design version.
- Mean on-state current, A.
- Voltage code (10=1000 V).
- Critical rate of rise of off-state voltage (6 \geq 500 V/ μs , 7 \geq 1000 V/ μs).
- Group of turn-off time ($du_D/dt=50\text{ V}/\mu\text{s}$, 6 \leq 20 μs , 7 \leq 16 μs , 8 \leq 12,5 μs).
- Group of turn-on time (3 \leq 2,5 μs , 4 \leq 2,0 μs , 5 \leq 1,6 μs).



Tightening torque : 40 \div 60 Nm

Weight : 380 grams

Mounting of thyristors with a rigid cathode gate should be carried through a flexible conductor.